SCBS052B - JULY 1990 - REVISED MAY 1994

- State-of-the-Art BiCMOS Design Significantly Reduces I<sub>CCZ</sub>
- High-Impedance State During Power-Up and Power-Down
- 3-State Outputs Drive Bus Lines or Buffer-Memory Address Registers
- ESD Protection Exceeds 2000 V Per MIL-STD-883C Method 3015
- Package Options Include Plastic Small-Outline (D) Packages and Standard Plastic 300-mil DIPs (N)

#### 

**DORNPACKAGE** 

#### description

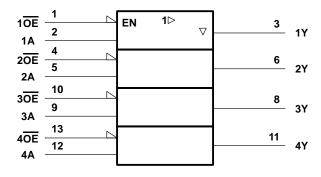
The SN64BCT125A bus buffer features independent line drivers with 3-state outputs. Each output is disabled when the associated output-enable  $(\overline{OE})$  input is high.

The SN64BCT125A is characterized for operation from -40°C to 85°C and 0°C to 70°C.

# FUNCTION TABLE (each buffer)

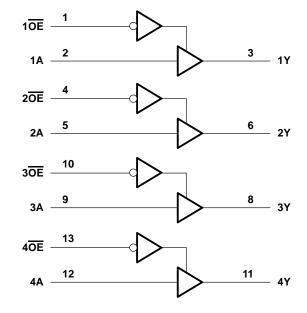
INP	JTS	OUTPUT
OE	Α	Y
L	Н	Н
L	L	L
Н	X	Z

## logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

#### logic diagram (positive logic)





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#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	– 0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)	$\ldots$ – 0.5 V to 7 V
Voltage range applied to any output in the disabled or power-off state, VO	$\dots$ - 0.5 V to 5.5 V
Voltage range applied to any output in the high state, V <sub>O</sub>	$\dots$ – 0.5 V to V <sub>CC</sub>
Current into any output in the low state	128 mA
Operating free-air temperature range	– 40°C to 85°C
Storage temperature range	– 65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
lik	Input clamp current			-18	mA
loh	High-level output current			-15	mA
loL	Low-level output current			64	mA
TA	Operating free-air temperature	-40		85	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
V <sub>IK</sub>	$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA				-1.2	V
V	V <sub>CC</sub> = 4.5 V	$I_{OH} = -3 \text{ mA}$	I <sub>OH</sub> = -3 mA				V
VOH	VCC = 4.5 V	$I_{OH} = -15 \text{ mA}$		2	3.1		V
$V_{OL}$	$V_{CC} = 4.5 \text{ V},$	I <sub>OH</sub> = 64 mA			0.42	0.55	V
lozh	$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$				50	μΑ
lozL	$V_{CC} = 5.5 V,$	V <sub>O</sub> = 0.5 V				-50	μΑ
loz	$V_{CC} = 0$ to 1.3 V (power up)	V <sub>O</sub> = 2.7 V or 0.5 V, OE	OE at 0.8 V			± 50	μА
loz	$V_{CC} = 1.3 \text{ V to 0 (power down)}$	V() = 2.7 V OI 0.3 V,	OE at 0.6 V			± 50	μΑ
lį	$V_{CC} = 0$ ,	V <sub>I</sub> = 7 V				0.1	mA
lН	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 2.7 V				25	μΑ
I <sub>IL</sub>	$V_{CC} = 5.5 V,$	V <sub>I</sub> = 0.5 V				-20	μΑ
los§	$V_{CC} = 5.5 V,$	VO = 0		-100		-225	mA
ICCL	V <sub>CC</sub> = 5.5 V				46	49	mA
IССН	V <sub>CC</sub> = 5.5 V				19	31	mA
Iccz	V <sub>CC</sub> = 5.5 V				6	14	mA
C <sub>i</sub>	$V_{CC} = 5 V$ ,	$V_{ } = 2.5 \text{ V or } 0.5 \text{ V}$			4		pF
Co	V <sub>CC</sub> = 5 V,	$V_0 = 2.5 \text{ V or } 0.5 \text{ V}$			9		pF

<sup>‡</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>§</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

### switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)		$V_{CC}$ = 5 V, $C_L$ = 50 pF, $R1$ = 500 $\Omega$ , $R2$ = 500 $\Omega$ ,		$V_{CC}$ = 4.5 V to 5.5 V, $C_L$ = 50 pF, R1 = 500 Ω, R2 = 500 Ω				UNIT	
			T <sub>A</sub> = 25°C		T <sub>A</sub> = -40°C to 85°C		T <sub>A</sub> = 0°C to 70°C			
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	А	Y	1.6	3.5	5.2	1.6	6	1.6	5.7	ns
<sup>t</sup> PHL			2.7	5	6.9	2.7	8	2.7	7.7	
<sup>t</sup> PZH	ŌĒ	Y	3.4	6.7	9	3.4	11.1	3.4	10.3	ns
<sup>t</sup> PZL		ī	5	8.2	10.4	5	12.8	5	11.7	115
<sup>t</sup> PHZ	ŌĒ	ŌĒ Y	3	5.8	7.4	3	9.4	3	8.9	ns
t <sub>PLZ</sub>	OL .	1	2.8	5.5	7.3	2.8	9.9	2.8	8.6	119

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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